

# Pedro Luis Grande

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/7275871/publications.pdf>

Version: 2024-02-01

181  
papers

3,355  
citations

147726

31  
h-index

214721

47  
g-index

183  
all docs

183  
docs citations

183  
times ranked

1591  
citing authors

#	ARTICLE	IF	CITATIONS
1	Impact Features Induced by Single Fast Ions of Different Charge-State on Muscovite Mica. <i>Atoms</i> , 2021, 9, 17.	0.7	5
2	Ion implantation in $\hat{\text{I}}^2\text{-Ga}_2\text{O}_3$ : Physics and technology. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 2021, 39, .	0.9	45
3	Bohr's stopping-power formula derived for a classical free-electron gas. <i>Physical Review A</i> , 2021, 104, .	1.0	3
4	Fluorination of graphene leads to susceptibility for nanopore formation by highly charged ion impact. <i>Physical Review Materials</i> , 2021, 5, .	0.9	7
5	Peeling graphite layer by layer reveals the charge exchange dynamics of ions inside a solid. <i>Communications Physics</i> , 2021, 4, .	2.0	13
6	Angle-dependent charge exchange and energy loss of slow highly charged ions in freestanding graphene. <i>Physical Review A</i> , 2021, 104, .	1.0	5
7	Ion tracks in ultrathin polymer films: The role of the substrate. <i>Current Applied Physics</i> , 2021, 32, 91-97.	1.1	3
8	Depth profiling of ion-implanted samples by high-energy electron scattering. <i>Journal Physics D: Applied Physics</i> , 2020, 53, 135304.	1.3	3
9	Stopping and straggling of $60\hat{\text{a}}\text{€}250\text{-keV}$ backscattered protons on nanometric Pt films. <i>Physical Review A</i> , 2020, 102, .	1.0	10
10	Elucidating the capability of electron backscattering for 3D nano-structure determination. <i>Journal Physics D: Applied Physics</i> , 2020, 53, 425103.	1.3	0
11	Vanishing influence of the band gap on the charge exchange of slow highly charged ions in freestanding single-layer $\langle \text{mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML"} \rangle \langle \text{mml:msub} \rangle \langle \text{mml:mi} \rangle \text{MoS} \langle \text{mml:mi} \rangle \langle \text{mml:mn} \rangle 2 \langle \text{mml:mh} \rangle \langle \text{mml:msub} \rangle \langle \text{mml:mn} \rangle 15 \langle \text{mml:msup} \rangle \langle \text{mml:mi} \rangle \text{S} \langle \text{mml:mi} \rangle \langle \text{mml:mn} \rangle 2 \langle \text{mml:mh} \rangle \langle \text{mml:msub} \rangle \langle \text{mml:mn} \rangle 15 \langle \text{mml:msup} \rangle \langle \text{mml:mi} \rangle \text{S} \langle \text{mml:mi} \rangle$ . <i>Physical Review B</i> , 2020, 102, .	1.1	15
12	The effect of ion implantation on reflection electron energy loss spectroscopy: The case of Au implanted Al films. <i>Journal of Electron Spectroscopy and Related Phenomena</i> , 2020, 240, 146935.	0.8	0
13	Unraveling energy loss processes of low energy heavy ions in 2D materials. <i>Communications Physics</i> , 2019, 2, .	2.0	28
14	Unraveling structural and compositional information in 3D FinFET electronic devices. <i>Scientific Reports</i> , 2019, 9, 11629.	1.6	14
15	Profiling As plasma doped Si/SiO <sub>2</sub> with molecular ions. <i>Thin Solid Films</i> , 2019, 692, 137536.	0.8	1
16	Extension schemes of the dielectric function, and their implications for ion stopping calculations. <i>Journal of Physics and Chemistry of Solids</i> , 2019, 133, 187-196.	1.9	2
17	Round-robin test of medium-energy ion scattering for quantitative depth profiling of ultrathin HfO <sub>2</sub> /SiO <sub>2</sub> /Si films. <i>Surface and Interface Analysis</i> , 2019, 51, 712-721.	0.8	3
18	Nonlinear stopping effects of slow ions in a no-free-electron system: Titanium nitride. <i>Physical Review A</i> , 2019, 100, .	1.0	12

#	ARTICLE	IF	CITATIONS
19	Characterization of oxygen self-diffusion in TiO <sub>2</sub> resistive-switching layers by nuclear reaction profiling. Nuclear Instruments & Methods in Physics Research B, 2019, 441, 8-11.	0.6	0
20	Modelling the contribution of semi-core electrons to the dielectric function. Journal of Physics and Chemistry of Solids, 2019, 124, 242-249.	1.9	9
21	Round-Robin Test of Medium-Energy Ion Scattering for Quantitative Depth Profiling of Ultrathin HfO <sub>2</sub> /SiO <sub>2</sub> /Si Films. Journal of Surface Analysis (Online), 2019, 26, 96-97.	0.1	0
22	Stopping cross section of vanadium for H + and He + ions in a large energy interval deduced from backscattering spectra. Nuclear Instruments & Methods in Physics Research B, 2018, 424, 43-51.	0.6	16
23	Stopping power of cluster ions in a free-electron gas from partial-wave analysis. Physical Review A, 2018, 98, .	1.0	11
24	Unveiling the Mechanisms Governing the Exchange Coupling and Coercivity Modifications in Annealed or Ion-Irradiated $\text{MnO}_x/\text{MnO}$ Heterostructures. Physical Review Applied, 2018, 10, .	1.5	3
25	The influence of shallow core levels on the shape of REELS spectra. Journal of Electron Spectroscopy and Related Phenomena, 2018, 229, 42-46.	0.8	5
26	Room temperature synthesis of HfO <sub>2</sub> /HfO <sub>x</sub> heterostructures by ion-implantation. Nanotechnology, 2018, 29, 425601.	1.3	6
27	A comparison of the analysis of non-centrosymmetric materials based on ion and electron beams. Nuclear Instruments & Methods in Physics Research B, 2018, 431, 31-37.	0.6	1
28	Simple model dielectric functions for insulators. Journal of Physics and Chemistry of Solids, 2017, 104, 192-197.	1.9	17
29	Charge-state related effects in sputtering of LiF by swift heavy ions. Nuclear Instruments & Methods in Physics Research B, 2017, 392, 94-101.	0.6	19
30	Extracting the dielectric function from high-energy REELS measurements. Surface and Interface Analysis, 2017, 49, 809-821.	0.8	10
31	How the choice of model dielectric function affects the calculated observables. Nuclear Instruments & Methods in Physics Research B, 2017, 407, 97-109.	0.6	11
32	Oxygen diffusion in TiO <sub>2</sub> films studied by electron and ion Rutherford backscattering. Thin Solid Films, 2017, 629, 97-102.	0.8	23
33	Vicinage effect in the energy loss of H <sub>2</sub> dimers: Experiment and calculations based on time-dependent density-functional theory. Physical Review A, 2017, 95, .	1.0	12
34	Unveiling the Inner Structure of PtPd Nanoparticles. Journal of Physical Chemistry C, 2017, 121, 19461-19466.	1.5	9
35	Ground- and excited-state scattering potentials for the stopping of protons in an electron gas. Journal of Physics B: Atomic, Molecular and Optical Physics, 2017, 50, 185201.	0.6	12
36	A comparison of ERBS spectra of compounds with Monte Carlo simulations. Surface and Interface Analysis, 2016, 48, 415-421.	0.8	6

#	ARTICLE	IF	CITATIONS
37	Alternative treatment for the energy-transfer and transport cross section in dressed electron-ion binary collisions. <i>Physical Review A</i> , 2016, 94, .	1.0	17
38	On the use of MEIS cartography for the determination of Si $\times$ Ge $\times$ thin-film strain. <i>Thin Solid Films</i> , 2016, 611, 101-106.	0.8	5
39	Morphological and compositional characteristics of bimetallic core@shell nanoparticles revealed by MEIS. <i>Applied Surface Science</i> , 2015, 330, 164-171.	3.1	9
40	Fluctuation conductivity and the chiral glass state in disordered $\langle \text{mml:math altimg="si6.gif" overflow="scroll" xmlns:xocs="http://www.elsevier.com/xml/xocs/dtd" xmlns:xs="http://www.w3.org/2001/XMLSchema" xmlns:xsi="http://www.w3.org/2001/XMLSchema-instance" xmlns="http://www.elsevier.com/xml/ja/dtd" xmlns:ja="http://www.elsevier.com/xml/ja/dtd" xmlns:mml="http://www.w3.org/1998/Math/MathML" xmlns:tb="http://www.elsevier.com/xml/common/table/dtd" xmlns:tbl_struct="http://www.elsevier.com/xml/common/table/dtd" xmlns:stb="http://www.elsevier.com/xml/common/stb/dtd" xmlns:td="http://www.w3.org/1998/Math/MathML" > < mml:msup > < mml:mrow > < mml:msub > < mml:mi mathvariant="normal" > H < /mml:mi > < mml:mn > 2 < /mml:mn > < /mml:mrow > < mml:mo > + < /mml:mo > < /mml:msup > < /mml:math >$ traversing thin films. <i>Physical Review A</i> , 2015, 91, .	0.6	2
41	Neutralization and wake effects on the Coulomb explosion of swift $\langle \text{mml:math altimg="si6.gif" overflow="scroll" xmlns:xocs="http://www.elsevier.com/xml/xocs/dtd" xmlns:xs="http://www.w3.org/2001/XMLSchema" xmlns:xsi="http://www.w3.org/2001/XMLSchema-instance" xmlns="http://www.elsevier.com/xml/ja/dtd" xmlns:ja="http://www.elsevier.com/xml/ja/dtd" xmlns:mml="http://www.w3.org/1998/Math/MathML" xmlns:tb="http://www.elsevier.com/xml/common/table/dtd" xmlns:tbl_struct="http://www.elsevier.com/xml/common/table/dtd" xmlns:stb="http://www.elsevier.com/xml/common/stb/dtd" xmlns:td="http://www.w3.org/1998/Math/MathML" > < mml:msup > < mml:mrow > < mml:msub > < mml:mi mathvariant="normal" > H < /mml:mi > < mml:mn > 2 < /mml:mn > < /mml:mrow > < mml:mo > + < /mml:mo > < /mml:msup > < /mml:math >$ traversing thin films. <i>Physical Review A</i> , 2015, 91, .	1.0	6
42	High-energy electron scattering from TiO <sub>2</sub> surfaces. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2015, 354, 332-339.	0.6	8
43	Confinement Effects of Ion Tracks in Ultrathin Polymer Films. <i>Physical Review Letters</i> , 2015, 114, 118302.	2.9	30
44	Antiparallel interface coupling evidenced by negative rotatable anisotropy in IrMn/NiFe bilayers. <i>Journal of Applied Physics</i> , 2015, 117, .	1.1	12
45	Transverse voltage and chiral glass transition in $\langle \text{mml:math altimg="si8.gif" overflow="scroll" xmlns:xocs="http://www.elsevier.com/xml/xocs/dtd" xmlns:xs="http://www.w3.org/2001/XMLSchema" xmlns:xsi="http://www.w3.org/2001/XMLSchema-instance" xmlns="http://www.elsevier.com/xml/ja/dtd" xmlns:ja="http://www.elsevier.com/xml/ja/dtd" xmlns:mml="http://www.w3.org/1998/Math/MathML" xmlns:tb="http://www.elsevier.com/xml/common/table/dtd" xmlns:tbl_struct="http://www.elsevier.com/xml/common/table/dtd" xmlns:stb="http://www.elsevier.com/xml/common/stb/dtd" xmlns:td="http://www.w3.org/1998/Math/MathML" > < mml:msup > < mml:mrow > < mml:msub > < mml:mrow > < mml:mtext > YBa < /mml:mtext > < /mml:mrow > < mml:mrow > < mml:mn > 2 < /mml:mn > < /mml:mrow >$ Physica C: Superconductivity and Its Applications, 2014, 506, 87-93.	0.6	3
46	The use of electron Rutherford backscattering to characterize novel electronic materials as illustrated by a case study of sputter-deposited NbO $\times$ films. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2014, 340, 58-62.	0.6	15
47	Oxygen Self-Diffusion in $\langle \text{mml:math altimg="si8.gif" overflow="scroll" xmlns:xocs="http://www.elsevier.com/xml/xocs/dtd" xmlns:xs="http://www.w3.org/2001/XMLSchema" xmlns:xsi="http://www.w3.org/2001/XMLSchema-instance" xmlns="http://www.elsevier.com/xml/ja/dtd" xmlns:ja="http://www.elsevier.com/xml/ja/dtd" xmlns:mml="http://www.w3.org/1998/Math/MathML" xmlns:tb="http://www.elsevier.com/xml/common/table/dtd" xmlns:tbl_struct="http://www.elsevier.com/xml/common/table/dtd" xmlns:stb="http://www.elsevier.com/xml/common/stb/dtd" xmlns:td="http://www.w3.org/1998/Math/MathML" > < mml:msup > < mml:mrow > < mml:msub > < mml:mrow > < mml:mtext > YBa < /mml:mtext > < /mml:mrow > < mml:mrow > < mml:mn > 2 < /mml:mn > < /mml:mrow >$ by Electron Spectroscopy. <i>Physical Review Letters</i> , 2014, 112, 175901.	2.9	25
48	MEIS, TEM and GISAXS investigation of buried Pb nanoislands in SiO <sub>2</sub> /Si interface. <i>Applied Surface Science</i> , 2014, 321, 80-85.	3.1	2
49	Quantitative Compositional Profiling of Conjugated Quantum Dots with Single Atomic Layer Depth Resolution via Time-of-Flight Medium-Energy Ion Scattering Spectroscopy. <i>Analytical Chemistry</i> , 2014, 86, 1091-1097.	3.2	23
50	The relation between the electron energy loss spectra of hafnia and its dielectric function. <i>Surface Science</i> , 2014, 630, 1-8.	0.8	14
51	Ultrafast electronic processes in an insulator: The Be and O sites in BeO. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2013, 317, 48-55.	0.6	6
52	Determination of film thicknesses through the breakup of H <sub>2</sub> <sup>+</sup> ions. <i>Surface Science</i> , 2013, 608, 292-296.	0.8	9
53	Exploring the Barkas effect with keV-electron scattering. <i>Physical Review A</i> , 2013, 88, .	1.0	10
54	Determination of thickness and composition of high-k dielectrics using high-energy electrons. <i>Applied Physics Letters</i> , 2013, 103, 071911.	1.5	11

#	ARTICLE	IF	CITATIONS
55	Skimming-trajectory effect for energy loss of medium-energy He ions passing along major crystal axes of KI(001) and RbI(001). <i>Physical Review A</i> , 2013, 87, .	1.0	2
56	A high-energy electron scattering study of the electronic structure and elemental composition of O-implanted Ta films used for the fabrication of memristor devices. <i>Journal of Applied Physics</i> , 2013, 114, 073508.	1.1	13
57	New approach for structural characterization of planar sets of nanoparticles embedded into a solid matrix. <i>Scientific Reports</i> , 2013, 3, 3414.	1.6	5
58	Structural characterization of CdSe/ZnS quantum dots using medium energy ion scattering. <i>Applied Physics Letters</i> , 2012, 101, .	1.5	15
59	Iron-based bimagnetic core/shell nanostructures in SiO <sub>2</sub> : a TEM, MEIS, and energy-resolved XPS analysis. <i>Journal of Nanoparticle Research</i> , 2012, 14, 1.	0.8	11
60	Stopping of protons – Improved accuracy of the UCA model. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2012, 273, 1-5.	0.6	23
61	Structural control of gold nanoparticles self-assemblies by layer-by-layer process. <i>Nanoscale</i> , 2011, 3, 1717.	2.8	12
62	Energy loss of swift H <sub>2</sub> and H <sub>3</sub> molecules in gold: Vicinage effects. <i>Physical Review B</i> , 2011, 83, .	1.1	13
63	Ion irradiation effects on the exchange bias in IrMn/Co films. <i>Journal of Applied Physics</i> , 2011, 109, .	1.1	18
64	Cluster ion emission from LiF induced by MeV Nq+ projectiles and <sup>252</sup> Cf fission fragments. <i>European Physical Journal D</i> , 2011, 63, 391-400.	0.6	9
65	Depth profiling techniques: how PIXE compares to NRP and MEIS?. <i>X-Ray Spectrometry</i> , 2011, 40, 157-161.	0.9	1
66	Ultrafast band-structure variations induced by fast Au ions in BeO. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2011, 269, 959-963.	0.6	1
67	Structural characterization of Pb nanoislands in SiO <sub>2</sub> /Si interface synthesized by ion implantation through MEIS analysis. <i>Surface Science</i> , 2011, 605, 654-658.	0.8	11
68	Introducing electron capture into the unitary-convolution-approximation energy-loss theory at low velocities. <i>Physical Review A</i> , 2011, 84, .	1.0	47
69	Al-K-Auger energy spectra: Probing the electron dynamics in ion-solid interactions. <i>Bulletin of the Russian Academy of Sciences: Physics</i> , 2010, 74, 192-200.	0.1	0
70	Energy loss of argon in a laser-generated carbon plasma. <i>Physical Review E</i> , 2010, 81, 026401.	0.8	40
71	Evidence for an Ultrafast Breakdown of the BeO Band Structure Due to Swift Argon and Xenon Ions. <i>Physical Review Letters</i> , 2010, 105, 187603.	2.9	11
72	Role of electronic excitations in the energy loss of H <sub>2</sub> +projectiles in high- $\hat{\rho}$ materials. <i>Physical Review B</i> , 2009, 80, .	1.1	6

#	ARTICLE	IF	CITATIONS
73	Direct Observation and Theory of Trajectory-Dependent Electronic Energy Losses in Medium-Energy Ion Scattering. <i>Physical Review Letters</i> , 2009, 102, 096103.	2.9	14
74	Characterization of nanoparticles through medium-energy ion scattering. <i>Journal of Applied Physics</i> , 2009, 106, .	1.1	51
75	Optical oscillator strengths, mean excitation energy, shell corrections and experimental values for stopping power. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2009, 267, 2471-2474.	0.6	3
76	Isotopic labeling study of oxygen diffusion in amorphous LaScO <sub>3</sub> high- $\hat{p}$ films on Si(100) and its effects on the electrical characteristics. <i>Applied Physics A: Materials Science and Processing</i> , 2009, 96, 447-451.	1.1	5
77	Convolution approximation for the energy loss, ionization probability and straggling of fast ions. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2009, 267, 859-865.	0.6	60
78	Experimental and theoretical studies of the energy-loss straggling of H and He ion beams in HfO <sub>2</sub> films. <i>European Physical Journal D</i> , 2009, 54, 65-70.	0.6	9
79	High-energy ion beam irradiation of Co/NiFe/Co/Cu multilayers: Effects on the structural, transport and magnetic properties. <i>Thin Solid Films</i> , 2008, 516, 2087-2093.	0.8	4
80	Search for short-time phase effects in the electronic damage evolution " A case study with silicon. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2008, 266, 1287-1293.	0.6	10
81	Direct Evidence for Projectile Charge-State Dependent Crater Formation Due to Fast Ions. <i>Physical Review Letters</i> , 2008, 101, 167601.	2.9	32
82	Analytical energy loss distribution for accurate high resolution depth profiling using medium energy ion scattering. <i>Applied Physics Letters</i> , 2008, 92, 164102.	1.5	9
83	Controlled rotation of the exchange-bias direction in IrMn $\hat{\cdot}$ Cu $\hat{\cdot}$ Co via ion irradiation. <i>Applied Physics Letters</i> , 2008, 93, .	1.5	31
84	Impact-parameter dependence of the energy loss of fast molecular clusters in hydrogen. <i>Physical Review A</i> , 2008, 77, .	1.0	3
85	Signature of plasmon excitations in the stopping ratio of fast hydrogen clusters. <i>Physical Review B</i> , 2008, 77, .	1.1	19
86	Asymmetric line shapes for medium energy H and He ions undergoing a large-angle collision. <i>Physical Review B</i> , 2008, 78, .	1.1	16
87	Indications for Enhanced Auger-Electron Absorption in a Hot-Electron Gas. <i>Physical Review Letters</i> , 2007, 99, 197602.	2.9	5
88	Advanced ion energy loss models: Applications to subnanometric resolution elemental depth profiling. <i>Surface Science</i> , 2007, 601, 5559-5570.	0.8	16
89	An analytical energy-loss line shape for high depth resolution in ion-beam analysis. <i>Nuclear Instruments &amp; Methods in Physics Research B</i> , 2007, 256, 92-96.	0.6	38
90	Inelastic energy loss in 100 $\hat{\sim}$ keVH $\hat{+}$ scattering from single atoms: Theory and experiment for K, Rb, and Cs. <i>Physical Review B</i> , 2006, 74, .	1.1	6

#	ARTICLE	IF	CITATIONS
91	Interplay between the Coulomb explosion and vicinage effects studied using H <sub>2</sub> +molecules under channeling conditions. Physical Review B, 2006, 73, .	1.1	5
92	INNER-SHELL COLLECTIVE EFFECTS FOR PROTONS BACKSCATTERED FROM THE AL(110) SURFACE. , 2006, , .		0
93	Impact-parameter dependence of the electronic energy loss of fast cluster projectiles. Nuclear Instruments & Methods in Physics Research B, 2005, 230, 17-23.	0.6	2
94	The influence of the Coulomb explosion on the energy loss of $\text{Si}^5$ . overflow="scroll" xmlns:xocs="http://www.elsevier.com/xml/xocs/dtd" xmlns:xs="http://www.w3.org/2001/XMLSchema" xmlns:xsi="http://www.w3.org/2001/XMLSchema-instance" xmlns="http://www.elsevier.com/xml/ja/dtd" xmlns:ja="http://www.elsevier.com/xml/ja/dtd" xmlns:mml="http://www.w3.org/1998/Math/MathML" xmlns:tb="http://www.elsevier.com/xml/common/table/dtd" xmlns:sb="http://www.elsevier.com/xml/co	0.6	5
95	Electronic energy-density effects in ion tracks of metals. Nuclear Instruments & Methods in Physics Research B, 2005, 230, 426-430.	0.6	12
96	Energy loss in medium-energy ion scattering: A combined theoretical and experimental study of the model system Y on Si(111). Physical Review B, 2005, 72, .	1.1	11
97	Observation of collective inner-shell effects for protons backscattered from the Al(110) surface. Physical Review A, 2005, 72, .	1.0	2
98	Electronic energy loss of channeled ions: The giant Barkas effect. Physical Review A, 2004, 70, .	1.0	9
99	Nonperturbative treatment of medium-energy proton scattering under shadowing-blocking conditions in Al(110). Physical Review B, 2004, 69, .	1.1	13
100	Contribution of close collisions to the Barkas effect: The classical picture. Physical Review A, 2004, 70, .	1.0	13
101	Coulomb heating of channeled H <sub>2</sub> +and H <sub>3</sub> +molecules in Si. Physical Review B, 2004, 69, .	1.1	14
102	Random energy loss and straggling study of <sup>9</sup> Be ions in silicon. Nuclear Instruments & Methods in Physics Research B, 2004, 219-220, 246-250.	0.6	5
103	Non-equilibrium emission of secondary ions from BeO films sputtered by swift gold ions. Nuclear Instruments & Methods in Physics Research B, 2004, 225, 72-77.	0.6	13
104	Ionization and Energy Loss Beyond Perturbation Theory. Advances in Quantum Chemistry, 2004, 45, 7-46.	0.4	26
105	Energy loss of helium ions in zinc. Physical Review A, 2004, 69, .	1.0	13
106	Femtosecond dynamics "snapshots" of the early ion-track evolution. Nuclear Instruments & Methods in Physics Research B, 2004, 225, 4-26.	0.6	34
107	Spectroscopy of Si-Auger electrons from the center of heavy-ion tracks. Nuclear Instruments & Methods in Physics Research B, 2003, 209, 26-31.	0.6	5
108	The role of basic energy-loss processes in layer-resolved surface investigations with ions. Current Applied Physics, 2003, 3, 35-37.	1.1	1

#	ARTICLE	IF	CITATIONS
109	Experimental energy straggling of protons in SiO <sub>2</sub> . Physical Review A, 2003, 68, .	1.0	16
110	Random and channeling stopping powers of He and Li ions in Si. Physical Review B, 2002, 65, .	1.1	21
111	The unitary convolution approximation for heavy ions. Nuclear Instruments & Methods in Physics Research B, 2002, 195, 55-63.	0.6	74
112	Random stopping power and energy straggling of ions into amorphous Si target. Nuclear Instruments & Methods in Physics Research B, 2002, 190, 79-83.	0.6	12
113	Energy loss measurements of H <sub>2</sub> and H <sub>3</sub> molecular beams along random and directions of Si. Nuclear Instruments & Methods in Physics Research B, 2002, 190, 74-78.	0.6	2
114	Channeling energy loss of O ions in Si: The Barkas effect. Nuclear Instruments & Methods in Physics Research B, 2002, 193, 172-177.	0.6	6
115	Si-Auger electrons from the center of nuclear tracks. Nuclear Instruments & Methods in Physics Research B, 2002, 193, 705-712.	0.6	16
116	Ion tracks "quasi one-dimensional nano-structures. Applied Surface Science, 2001, 182, 286-292.	3.1	19
117	Energy dissipation of fast heavy ions in matter. Nuclear Instruments & Methods in Physics Research B, 2001, 175-177, 1-11.	0.6	61
118	Random energy loss and straggling study of Li into Si. Nuclear Instruments & Methods in Physics Research B, 2001, 175-177, 98-101.	0.6	4
119	Angular dependence for the energy loss of channeled He ions near the Si and directions. Nuclear Instruments & Methods in Physics Research B, 2001, 174, 407-413.	0.6	8
120	Improved charge-state formulas. Nuclear Instruments & Methods in Physics Research B, 2001, 175-177, 125-131.	0.6	241
121	Limitations to depth resolution in ion scattering experiments. Nuclear Instruments & Methods in Physics Research B, 2001, 183, 16-24.	0.6	26
122	Electronic energy loss of H <sub>3</sub> <sup>+</sup> ion clusters in SiO <sub>2</sub> films. Physical Review A, 2001, 64, .	1.0	12
123	Giant Barkas Effect Observed for Light Ions Channeling in Si. Physical Review Letters, 2001, 86, 1482-1485.	2.9	34
124	Charge equilibration of He ions in the Si channel. Nuclear Instruments & Methods in Physics Research B, 2000, 161-163, 96-100.	0.6	3
125	Molecular H <sub>2</sub> and H <sub>3</sub> energy loss measurements along the Si "111" direction. Nuclear Instruments & Methods in Physics Research B, 2000, 161-163, 168-171.	0.6	5
126	Auger electrons from ion tracks. Nuclear Instruments & Methods in Physics Research B, 2000, 164-165, 353-364.	0.6	33



#	ARTICLE	IF	CITATIONS
127	Impact-parameter dependent energy loss of screened ions. Nuclear Instruments & Methods in Physics Research B, 2000, 164-165, 203-211.	0.6	57
128	Charge equilibration of energetic He ions in the Si channel. Nuclear Instruments & Methods in Physics Research B, 2000, 168, 321-328.	0.6	4
129	On the use of the backward Fokker-Planck equation to calculate range profiles. Nuclear Instruments & Methods in Physics Research B, 2000, 170, 45-52.	0.6	2
130	Impact-parameter dependence of the electronic energy loss. AIP Conference Proceedings, 2000, , .	0.3	0
131	Determination of the electron temperature in the thermal spike of amorphous carbon. Europhysics Letters, 1999, 47, 384-390.	0.7	36
132	Electronic stopping power of axial channeled Li ions in Si crystals. Nuclear Instruments & Methods in Physics Research B, 1999, 148, 164-167.	0.6	9
133	Damage of ion irradiated C60 films. Nuclear Instruments & Methods in Physics Research B, 1999, 149, 336-342.	0.6	29
134	Depth profiles and amorphization behavior under channeling conditions for low energy Bi ions implanted into Si crystals. Nuclear Instruments & Methods in Physics Research B, 1999, 149, 301-311.	0.6	5
135	A unitary convolution approximation for the impact-parameter dependent electronic energy loss. Nuclear Instruments & Methods in Physics Research B, 1999, 153, 1-9.	0.6	92
136	Indications for a new electron-ejection mechanism: Nuclear-track guided electrons induced by fast heavy ions in insulators. Nuclear Instruments & Methods in Physics Research B, 1998, 135, 466-470.	0.6	1
137	Angular dependent energy loss of 0.8-2.0 MeV He ions channeled along the Si [100] direction. Nuclear Instruments & Methods in Physics Research B, 1998, 136-138, 132-136.	0.6	12
138	Improved calculations of the electronic energy loss under channeling conditions. Nuclear Instruments & Methods in Physics Research B, 1998, 136-138, 125-131.	0.6	16
139	An experimental determination of electron temperatures in the center of nuclear tracks in amorphous carbon. Nuclear Instruments & Methods in Physics Research B, 1998, 146, 131-136.	0.6	27
140	Impact-parameter dependence of the electronic energy loss of fast ions. Physical Review A, 1998, 58, 3796-3801.	1.0	114
141	High Fluence Ion Irradiation of Thin Fullertte Films. Fullerenes, Nanotubes, and Carbon Nanostructures, 1998, 6, 911-962.	0.6	6
142	Angular dependence of the electronic energy loss of 800-keV He ions along the Si [100] direction. Physical Review B, 1997, 55, 4332-4342.	1.1	33
143	Indications of Nuclear-Track-Guided Electrons Induced by Fast Heavy Ions in Insulators. Physical Review Letters, 1997, 79, 1821-1824.	2.9	48
144	Electronic stopping power of B <sup>10</sup> in Si in random and [100] channeling directions. Physical Review B, 1997, 55, 13651-13657.	1.1	15

#	ARTICLE	IF	CITATIONS
145	Compaction of Fullerite Films after High Fluence Ion and Electron Bombardment. Fullerenes, Nanotubes, and Carbon Nanostructures, 1997, 5, 511-526.	0.6	5
146	Electronic stopping power of 10B channeled into the Si $\sim 100\%$ axial direction. Nuclear Instruments & Methods in Physics Research B, 1997, 127-128, 107-111.	0.6	0
147	Coupled-channel calculations of the electronic energy loss. Nuclear Instruments & Methods in Physics Research B, 1997, 132, 264-275.	0.6	22
148	Very large sputtering yields of ion irradiated C60 films. Physics Letters, Section A: General, Atomic and Solid State Physics, 1997, 226, 217-222.	0.9	16
149	Damage and sputtering of fullerene by low energy medium and heavy ions. Nuclear Instruments & Methods in Physics Research B, 1996, 113, 244-247.	0.6	12
150	Evidence for convoy-electron shifts due to induced potentials. Nuclear Instruments & Methods in Physics Research B, 1996, 115, 215-219.	0.6	6
151	Stopping mechanisms of negative heavy particles in gas targets. Nuclear Instruments & Methods in Physics Research B, 1996, 115, 106-110.	0.6	7
152	Nonperturbative treatment of the screened-Coulomb contribution of projectile-electron loss. Physical Review A, 1996, 54, 2983-2990.	1.0	31
153	Ion Implantation into Fullerene. Fullerenes, Nanotubes, and Carbon Nanostructures, 1996, 4, 535-552.	0.6	2
154	Comprehensive analysis of the stopping power of antiprotons and negative muons in He and gas targets. Journal of Physics B: Atomic, Molecular and Optical Physics, 1996, 29, 307-321.	0.6	65
155	Ranges in Si and lighter mono and multi-element targets. Materials Science and Engineering Reports, 1995, 15, 1-83.	14.8	47
156	Electronic stopping power of $\sim 100\%$ axial-channelled He ions in Si crystals. Nuclear Instruments & Methods in Physics Research B, 1995, 106, 51-54.	0.6	46
157	Dominant two-center electron-electron interactions in collisions of 120-MeVNe <sup>6+</sup> ions with gas targets. Physical Review A, 1995, 52, 387-391.	1.0	10
158	On classical calculations of the electronic stopping power at intermediate energies. Journal of Physics B: Atomic, Molecular and Optical Physics, 1995, 28, 425-433.	0.6	22
159	Double Ionization of Helium by 40 MeV Protons. Europhysics Letters, 1994, 27, 341-346.	0.7	6
160	Electronic stopping based on atomic and solid-state wavefunctions. Radiation Effects and Defects in Solids, 1994, null, 137-156.	0.4	21
161	Angular dependence of energy loss in proton-helium collisions. Physical Review Letters, 1994, 72, 2159-2162.	2.9	36
162	Range parameters of Er, Ga and F implanted into SiC films. Nuclear Instruments & Methods in Physics Research B, 1994, 85, 579-583.	0.6	5

#	ARTICLE	IF	CITATIONS
163	On the treatment of light-ion electronic stopping in dense matter. Nuclear Instruments & Methods in Physics Research B, 1994, 90, 10-19.	0.6	13
164	Range parameters of Au and Cs implanted into BN and SiC films. Nuclear Instruments & Methods in Physics Research B, 1993, 80-81, 53-57.	0.6	8
165	Nonperturbative stopping-power calculation for bare and neutral hydrogen incident on He. Physical Review A, 1993, 47, 1119-1122.	1.0	66
166	Influence of nuclear track potentials in insulators on the emission of target Auger electrons. Physical Review Letters, 1992, 69, 628-631.	2.9	72
167	On the Experimental Investigation of Ion Beam Mixing in Thin Film Bilayers, Study of the Fe-Al Case. Physica Status Solidi A, 1992, 129, 453-465.	1.7	10
168	Energy loss of slow ions: one-band calculation for alkaline metals. Physics Letters, Section A: General, Atomic and Solid State Physics, 1992, 163, 439-446.	0.9	25
169	Range parameters study of Pb and Au implanted into SiC films. Nuclear Instruments & Methods in Physics Research B, 1992, 64, 668-671.	0.6	17
170	Electronic stopping of protons at intermediate velocities. Nuclear Instruments & Methods in Physics Research B, 1992, 69, 10-17.	0.6	49
171	Range parameters of heavy ions implanted into boron films. Nuclear Instruments & Methods in Physics Research B, 1991, 59-60, 1-4.	0.6	15
172	Range parameters study of medium-heavy ions implanted into light substrates. Nuclear Instruments & Methods in Physics Research B, 1991, 61, 282-290.	0.6	59
173	Impact-parameter dependence of electronic energy loss and straggling of incident bare ions on H and He atoms by using the coupled-channel method. Physical Review A, 1991, 44, 2984-2992.	1.0	58
174	Range parameters of heavy ions implanted into Be films. Nuclear Instruments & Methods in Physics Research B, 1990, 45, 689-692.	0.6	22
175	Diffusion of Hf in $\gamma$ -Zr. Applied Physics A: Solids and Surfaces, 1990, 51, 29-33.	1.4	9
176	Range and thermal-behavior studies of Au and Bi implanted into photoresist films. Physical Review B, 1990, 41, 6145-6153.	1.1	33
177	High energy Li implanted profiles in silicon. Nuclear Instruments & Methods in Physics Research B, 1989, 39, 22-25.	0.6	7
178	Range profiles of medium and heavy ions implanted into SiO <sub>2</sub> . Nuclear Instruments & Methods in Physics Research B, 1988, 35, 17-20.	0.6	32
179	Range parameters of heavy ions implanted into C films. Nuclear Instruments & Methods in Physics Research B, 1988, 33, 122-124.	0.6	24
180	Thermal behavior and range distribution of <sup>209</sup> Bi implanted into the Al/V bilayer structure. Journal of Applied Physics, 1988, 63, 4431-4434.	1.1	0

#	ARTICLE	IF	CITATIONS
181	Projected ranges and range stragglings of Au and Bi implanted into carbon films and into SiO <sub>2</sub> . Nuclear Instruments & Methods in Physics Research B, 1987, 19-20, 25-27.	0.6	25